

GPT-12000 Series

AC/DC/IR/GB Electrical Safety Analyzer

FEATURES

- 200VA AC Test Capacity
- Comply with IEC 61010-2-034
- 7" TFT LCD
- Manual / Auto Mode
- True RMS Current Measurement
- Zero Crossing Turn-on Operation
- Controllable Ramp-up & Ramp-down Time
- Capacitive Load Testing Capability up to 47µF
- Statistics Function
- Sweep Function for DUT Characteristic Analysis
- USB Storage Available
- Rear Panel Output Available
- Interface : RS-232C, USB Host/Device, Signal I/O and GPIB (Opt.)
- Universal Power Input



GW Instek introduces the flagship model (200VA output capacity) safety analyzer-the GPT-12000 series, which is the first safety analyzer in the world to comply with IEC 61010-2-034 (Safety requirement for electrical requirement for measurement, control and laboratory use – particular requirements for measurement equipment for insulation resistance and test equipment for electric strength), which stipulates that the requirements of the software and hardware interfaces must be followed while designing high voltage and insulation resistance test and measurement instruments so as to ensure that users are provided with necessary protection and warning while using the instruments.

The GPT-12000 series safety analyzer has four models: GPT-12004 features AC/DC withstanding voltage test, insulation resistance test, AC ground bond test and continuity test; GPT-12003 conducts AC/DC withstanding voltage test, insulation resistance test, and continuity test; GPT-12002 carries out AC/DC withstanding voltage test and continuity test; GPT-12001 executes AC withstanding voltage test and continuity test. The entire series provides an output capacity of 200VA and utilizes a high-efficient PWM amplifier to effectively exclude the influence from the fluctuating input voltage or distorted waveforms so as to guarantee a stable high-voltage output while conducting AC withstanding voltage test on the DUT to meet the safety regulations such as IEC \leq EN \leq UL \leq CSA \leq GB \leq JIS that demand the test requirements for various electronic/electrical products or parts.

To comply with IEC 61010-2-034 requirements, the series takes into account of safety by adopting the double insulation design for input power supply and output voltage to enhance user safety. Additionally, the retracted on-off switch design (START key) and various (optional) mechanisms for test activation (for instance, press and hold for 1 second to activate, activation by pressing double keys, etc.) are incorporated into the series to avoid accidentally touching that results in high voltage/large current output causing damage and danger to products or users. High illumination LED lights (flashing or permanently lit) and a high volume audial indicator are included in designing the series to provide warnings of the status of the on-going tests or judgement results from the safety analyzer. On top of that, the DUT will be automatically discharged to the safe voltage (approximately 30V) after each test to prevent large residual test voltage from causing harm to users.

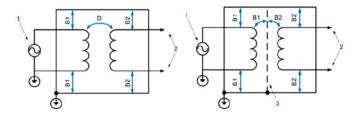
The series utilizes 7-inch color TFT LCD and inherits the consistent simplicity key design style of the product family to allow users to experience easy operations and a clear observation of the test results. The major test functions include AC withstanding voltage test (AC 5kV/40mA), DC withstanding voltage test (DC 6kV/10mA), insulation resistance test (DC 50V-1200V/50G Ω max.), ground bond test (AC 32A/650m Ω max.), and grounding continuity test (DC 100mA fixed/70 Ω max.). The series also collocates with superb output adjustment resolution, measurement resolution (AC withstanding voltage: 1µA; DC withstanding voltage: 0.1µA; insulation resistance: 0.1M Ω ; ground bond: 0.1M Ω ; continuity test: 0.01 Ω), controllable voltage ramp up and ramp down time settings, and upper/lower limit judgement settings, and large capacitance test capability (up to 47uF) for DUT with large capacitance such as surge absorber and large capacitance on the input terminal of EMC/EMI prevention. For Insulation resistance, provides 10mA pre-charged current (fixed) to first rapidly fully charge the DUT's capacitive load and then to conduct test and measurement so as to avoid misjudgment from fluctuating inrush current. All the above features of the series facilitate a more flexible execution of the required tests so that users can obtain accurate test and measurement results.

The statistic function is the highlight of the series. Test items, number of tests, judgement results are recoded after testing and the test results can be shown by bar graph on the display. Users can immediately learn the status of product tests and judgement distribution during the manufacturing process without using a PC. The other strong feature is the sweep function, which can be used for the analysis on product's crash point. Users can use the sweep mode to see the curve diagram of the test results after finishing the functional tests. Users can also select any time point during the process to analyze the relation between voltage and current (when ACW or DCW is selected). The test result of the certain period of time can be swept by setting start and stop time points to analyze the relation between voltage and current under that time frame. Furthermore, the tabular continuity test function can combine 10 manual memory sets to carry out automatic tests or 9 manual memory sets with one connection device to connect next automatic test so as to increase the test items of the continuity test. Users can obtain various test values and judgement results without switching to a different display screen.

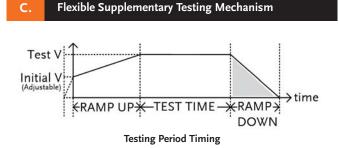
Other functions and features of the GPT-12000 series include 100 sets of manual test memory for the storage of different test conditions; rear output terminal for system integration; front panel remote control terminal mount/rear panel Signal I/O for users to conveniently control the analyzer's output/stop based upon the requirements. The USB storage function allows test results to be stored in the USB flash drive to save the trouble of using a PC, and the function is conducive to the follow-up data analysis. For users with the requirements of PC control and test results recording, the series also provides RS-232C, USB and GPIB (optional)

PANEL INTRODUCTION

	C C USB RS-232 GPIB USB Signal Rear Output
	1. Start & Stop Button 2. Function Selection Key 3. 7" LCD Display
<complex-block></complex-block>	 4. Navigator Key 5. Status Indicator (PASS/FAIL) 6. Wheel & Test Mode key 7. USB Host 8. REMOTE Terminal 9. Hi-Voltage Output Terminal & Indicator 10. Current Output Terminal & Return 11. Rear Output Terminal & Indicator 12. Series Port (RS-232C/USB device) 13. Signal I/O 14. GPIB (optional)



Providing the markets with safe electronic products is the responsibility of every manufacturer! Similarly, safety analyzer that tests whether electronic products meet safety regulations must attach the importance to the safety it provides! GPT-12000 is the world's first safety analyzer to comply with IEC 61010-2-034 (Safety requirement for electrical requirement for measurement, control and laboratory use – particular requirements for measurement equipment for insulation resistance and test equipment for electric strength). Apart from this, the safety considerations also include double insulation for input and output voltages, safe output/warning mechanism, post-test discharge mechanism, etc. to ensure user safety during the operation.



To make tests compliant with the test requirements of relevant safety regulations, the GPT-12000 series provides a more flexible output sequence setting starting from the start point of the test. Taking the AC/DC withstand voltage test as an example, the initial voltage can be set. Users determine the initial voltage ratio (i.e., the ratio of the rated test voltage), and then the voltage ramp up can also be set to reduce the risk of insulation breakdown or damage to the DUT caused by transient high voltages. After the rated test voltage is reached, the upper/lower limit judgement window, delay judgment and test timer mechanism can be set to assist users to conduct tests smoothly and correctly. The new voltage ramp down time setting allows users to test with a ramp down voltage to ne DUT.

With respect to the insulation resistance test, other than the newly added grounding mode to perform test in accordance with the actual grounding state of the DUT, the setting mechanism of the supplementary upper/lower limit judgement is also added to shorten the test time. The user-definable mode mechanisms include: STOP ON FAIL: The test is terminated as soon as the FAIL setting is met; STOP ON PASS: The test is terminated as long as the PASS setting is met, or TIMER: judgement is conducted when the timer time is reached.

E. Statistic and Analysis

PASS, FAIL Amounts & TOTAL Amounts





PASS & FAIL Amounts Distributions in Each Test Function Statistic

Analysis

The GPT-12000 series provides the statistic function, which can record the test functions and judgment results in the temporary storage area (60,000 lots max.). Users can immediately learn the test of each function during the test without using a PC. The distribution of the good products can be analyzed to understand the quality of the batch based on the data. If most of them fall at the critical point that is close to be categorized as defect product, the results can be found in the test process in time so as to improve the manufacturing process and stop the defect products from entering the markets to ensure the reliability of products after leaving the factory.

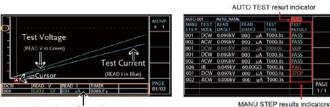
B. High Accuracy and High Resolution Testing Performance



High Adjustment & Measurement Resolution

For production tests and characteristic verification, the GPT-12000 series provides a withstand voltage test voltage (AC 5kV/DC 6kV) that can be adjusted in 1V steps with current measurement resolutions up to 1 μ A (ACW) or 0.1 μ A (DCW) to realize the small leakage current measurement for products or components. In addition, the insulation resistance test voltage can be adjusted in 50V steps from a DC output range of 50V to 1200V, and the resistance measurement resolution can reach 0.1MΩ. Since most safety regulations require AC power supply for ground bond test, the GPT-12000 series provides 8Vac (open) and 3A to 32Aac current for ground bond test with a resistance measurement resolution of 0.1mΩ. The entire series provides the continuity grounding test function with a 100mAdc (fixed) test source and a measurement resolution, users can perform various safety tests and verifications with high accuracy and reliability.

D. Sweep and Tabular Automatic Test



The values of point by cursor Sweep Function

Tabular Automatic Test

The GPT-12000 series features a unique sweep function, which displays a curve diagram of the test results of the DUT. Test readings are recorded point by point based on the applied test voltage or current and relevant settings (such as initial voltage, ramp up time, test time, or ramp down time). After the test is completed, users can learn the amount of applied energy (voltage or current) at a specific time point and the results of measurement parameters by moving the cursor position so as to help users understand the changes of the measurement parameters (current or resistance) during the test. The function can also be used to determine the critical break down of the DUT. With respect to the automatic test function, each automatic test has up to 10 manual test items and all related settings and result judgement are presented in a table, so that users can easily obtain the results of all test items at a time. Other than that, if there are multiple automatic test connection requirements, uses only need to select CON in the last item of the table to automatically connect the automatic measurement of the next position (such as AUTO-012~ AUTO-013)

E. Complete test Data retrieval Interface





SIGNAL IO Selection for AUTO Test (blue zone)

Usb Storage Function Signal I/O Self-defined Signal I/O

In order to facilitate users to analyze the results of the safety test, GPT-12000 provides the USB storage function in addition to its own statistic and analysis functions. When a USB is inserted and the storage function is activated, each time the test button (START) is pressed, the test results of all tests (every manual or automatic test item) are automatically saved to the USB in the form of a text file (txt) for follow-up analysis. For interface connections, the GPT-12000 series offers external control or a variety of remotely connected ports such as a signal I/O port that can be used to connect an external controller or PLC. The signal I/O's output signal pins can be self-defined so as to collocate with various PLC control requirements. Besides, the entire series is equipped with RS-232C and USB device (GPIB is optional) for easy retrieval of test data and results by connecting a PC.

CDECIEICATIO		
SPECIFICATIO		
AC WITHSTANDING Output-Voltage Range		0.05012/ 5.00012/
Output-Voltage Resolution	1	0.050kV~5.000kV
Output-Voltage Accuracy		±(1% of setting + 5V) [no load]
Maximum Rated Load		200 VA (5kV/40mA)
Maximum Rated Current Output-Voltage Waveform		40mA (0.5kV< V≦5kV); 10mA (0.05kV≦ V ≦0.5kV) Sine wave
Output-Voltage Frequency		50 Hz / 60 Hz selectable
Voltage Regulation		±(1% + 5V) [maximum rated load no load]
Voltmeter Accuracy		±(1% of reading + 5V) 1µA~40.00mA
Current Measurement Ran Current Best Resolution	ige	1μΑ / 10μΑ
Current Measurement Acc	curacy	$\pm (1.5\% \text{ of reading} + 30\mu\text{A})$
Window Comparator Met	nod	Yes
ARC Detect		Yes 0.1s~999.9s
RAMP UP (Rise Time) RAMP DOWN (Fall Time)		0.05~999.95
TIMER (Test Time)		OFF, 0.3s~999.9s
WAIT TIME GND		0.0s~999.9s ON/OFF
DC WITHSTANDING		
Output-Voltage Range		0.050kV~6.000kV
Output-Voltage Resolution	1	1V
Output-Voltage Accuracy Maximum Rated Load		±(1% of setting + 5V) [no load]
Maximum Rated Load		50W (5kV/10mA) 10mA (0.5kV< V ≦6kV); 2mA (0.05kV≦ V ≦0.5kV)
Voltage Regulation		±(1% + 5V) [maximum rated load no load]
Voltmeter Accuracy		±(1% of reading + 5V)
Current Measurement Ran Current Best Resolution	nge	1μΑ~10.00mA 0.1μΑ /1μΑ /1μΑ
Current Best Resolution Current Measurement Acc	curacy	0.1μΑ /1μΑ /10μΑ ±(1.5% of reading + 3μΑ) when I Reading < 1mA ; ±(1.5% of reading + 30μΑ) when I Reading≧1mA
Window Comparator Met		Yes
ARC Detect		Yes
RAMP UP (Rise Time) RAMP DOWN (Fall Time)		0.1s~999.9s 0.0s~999.9s
TIMER (Test Time)		OFF, 0.3s~999.9s
WAIT TIME		0.0s~999.9s
GND	E	ON/OFF
INSULATION RESISTANC	.E	50V~1200V dc
Output-Voltage Resolution	1	50V-1200V dc
Output-Voltage Accuracy		±(1% of setting + 5V) [no load]
Resistance Measurement		Measurement Range / Accuracy
	$50V \le V \le 100V$ $0.1M \Omega \sim 10.00G \Omega$ $150V \le V \le 450V$ $0.1M \Omega \sim 20.00G \Omega$	0.1MΩ~1MΩ : ±(5% of reading + 3 count); 1 MΩ~50MΩ : ±(5% of reading + 1 count); 51MΩ~2GΩ : ±(10% of reading + 1 count)
	130V = V = 130V = 0.1M Ω ~ 20.00G Ω	$0.1M\Omega \sim 1M\Omega$: $\pm (5\% \text{ of reading} + 3 \text{ count}); 1 M\Omega \sim 500M\Omega$: $\pm (5\% \text{ of reading} + 1 \text{ count});$
		501MΩ~9.999GΩ`: ±(10% of reading + 1 count); 10GΩ~50GΩ`: ±(20% of reading + 1 count)
Voltage Regulation		±(1% + 5V) [maximum rated load no load]
Voltmeter Accuracy Short-Circuit Current		±(1% of reading + 5V) 10mA max.
Output Impedance		
Window Comparator Met	nod	Yes
RAMP UP (Rise Time)		0.15-999.95
RAMP DOWN (Fall Time) TIMER (Test Time)		0.0s~999.9s 0.3s~999.9s
WAIT TIME		0.0s~999.9s
		ON/OFF
GND		
GND GROUND BOND		03.004-32.004.55
GND GROUND BOND Output-Current	n	03.00A-32.00A ac 0.01A
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy	n	0.01A 3A≤1≤8A : ±(1% of reading + 0.2A); 8A<1≤32A : ±(1% of reading + 0.05A)
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage	n	0.01A 3A≦I≦8A : ±(1% of reading + 0.2A); 8A <i≦32a +="" 0.05a)<br="" :="" of="" reading="" ±(1%="">8Vac max (open circuit)</i≦32a>
GND GROUND BOND Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency		0.01A 3A≦1≤8A: ±(1% of reading + 0.2A); 8A<1≦32A : ±(1% of reading + 0.05A) 8Vac max (open circuit) 50Hz/60Hz selectable
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage	Range	0.01A 3A≦I≦8A : ±(1% of reading + 0.2A); 8A <i≦32a +="" 0.05a)<br="" :="" of="" reading="" ±(1%="">8Vac max (open circuit)</i≦32a>
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement	Range Resolution Accuracy	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading} + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading} + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading} + 2 m\Omega)$
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl	Range Resolution Accuracy	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement	Range Resolution Accuracy	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading} + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading} + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading} + 2 m\Omega)$
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND	Range Resolution Accuracy	0.01A $3A \leq l \leq 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < l \leq 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST	Range Resolution Accuracy	0.01A $3A \leq 1 \leq 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \leq 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal ON/OFF
GND GROUND BOND Output-Current Resolution Output-Current Resolution Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current	Range Resolution Accuracy 10d	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement TIMER (Test Time) Test Method GND CONTINUITY TEST Ohmmeter Measurement Ohmmeter Measurement	Range Resolution Accuracy 10d Range Resolution	$\begin{array}{l} 0.01A\\ 3A \leqq 1 \le 8A : \pm (1\% \ of \ reading + 0.2A); \ 8A < 1 \leqq 32A : \pm (1\% \ of \ reading + 0.05A)\\ 8Vac \ max \ (open \ circuit)\\ 50Hz/60Hz \ selectable\\ 1m\Omega \sim 650m\Omega\\ 0.1m\Omega\\ \pm (1\% \ of \ reading + 2 \ m\Omega)\\ Yes\\ 0.35 - 999.9s\\ Four \ Terminal\\ ON/OFF\\ \hline \\ \hline 100mA \ dc \ (fixed)\\ 0.10\Omega\\ OID\\ \end{array}$
GND GROUND BOND Output-Current Resolution Output-Current Resolution Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement	Range Resolution Accuracy nod Range Resolution Accuracy	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.10Ω $\pm (10\% \text{ of reading } + 2 \Omega)$
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meti TIMER (Test Time) Test Method GND CONTINUITY TEST Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meti TIMER (Test Time)	Range Resolution Accuracy nod Range Resolution Accuracy	$\begin{array}{l} 0.01A\\ 3A \leqq 1 \le 8A : \pm (1\% \ of \ reading + 0.2A); \ 8A < 1 \leqq 32A : \pm (1\% \ of \ reading + 0.05A)\\ 8Vac \ max \ (open \ circuit)\\ 50Hz/60Hz \ selectable\\ 1m\Omega \sim 650m\Omega\\ 0.1m\Omega\\ \pm (1\% \ of \ reading + 2 \ m\Omega)\\ Yes\\ 0.35 - 999.9s\\ Four \ Terminal\\ ON/OFF\\ \hline \\ \hline 100mA \ dc \ (fixed)\\ 0.10\Omega\\ OID\\ \end{array}$
GND GROUND BOND Output-Current Resolution Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Mindow Comparator Meth TIMER (Test Time) MEMORY	Range Resolution Accuracy nod Range Resolution Accuracy	$\begin{array}{l} 0.01A\\ 3A & \leq 1 \leq 8A: \pm (1\% \ of \ reading + 0.2A); \ 8A < I \leq 32A: \pm (1\% \ of \ reading + 0.05A)\\ 8Vac \ max \ (open \ circuit)\\ 50Hz/60Hz \ selectable\\ 1 \ m\Omega - 650m\Omega\\ 0.1m\Omega\\ \pm (1\% \ of \ reading + 2 \ m\Omega)\\ Yes\\ 0.3s - 99.9s\\ Four \ Terminal\\ ON/OFF\\ \hline \\ \hline 100mA \ dc \ (fixed)\\ 0.10\Omega + 70.00\Omega\\ 0.01\Omega\\ \pm (10\% \ of \ reading + 2 \ \Omega)\\ Yes\\ 0.3s - 99.9s\\ \hline \end{array}$
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) MEMORY Single Step Memory	Range Resolution Accuracy tod Range Resolution Accuracy tod	$\begin{array}{l} 0.01A\\ 3A \leq 1 \leq 8A: \pm (1\% \ of \ reading + 0.2A); \ 8A < 1 \leq 32A: \pm (1\% \ of \ reading + 0.05A)\\ 8Vac \ max \ (open \ circuit)\\ SOHz/60Hz \ selectable\\ 1m\Omega \sim 650m\Omega\\ 0.1m\Omega\\ \pm (1\% \ of \ reading + 2 \ m\Omega)\\ Yes\\ 0.3s - 999.9s\\ \hline\\ \hline\\ \hline\\ 100mA \ dc \ (fixed)\\ 0.10\Omega\\ \pm (10\% \ of \ reading + 2 \ \Omega)\\ Yes\\ 0.3s - 999.9s\\ \hline\\\\\hline\\ MANU: 100 \ blocks\\ \hline\end{array}$
GND GROUND BOND Output-Current Resolution Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Mindow Comparator Meth TIMER (Test Time) MEMORY	Range Resolution Accuracy tod Range Resolution Accuracy tod	$\begin{array}{l} 0.01A\\ 3A & \leq 1 \leq 8A: \pm (1\% \ of \ reading + 0.2A); \ 8A < I \leq 32A: \pm (1\% \ of \ reading + 0.05A)\\ 8Vac \ max \ (open \ circuit)\\ 50Hz/60Hz \ selectable\\ 1 \ m\Omega - 650m\Omega\\ 0.1m\Omega\\ \pm (1\% \ of \ reading + 2 \ m\Omega)\\ Yes\\ 0.3s - 99.9s\\ Four \ Terminal\\ ON/OFF\\ \hline \\ \hline 100mA \ dc \ (fixed)\\ 0.10\Omega + 70.00\Omega\\ 0.01\Omega\\ \pm (10\% \ of \ reading + 2 \ \Omega)\\ Yes\\ 0.3s - 99.9s\\ \hline \end{array}$
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Mindow Comparator Meth TIMER (Test Time) MEMORY Single Step Memory Automatic Testing Memori INTERFACE Standard (Front)	Range Resolution Accuracy tod Range Resolution Accuracy tod	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal ON/OFF 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ 0.10Ω $\pm (10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) MEMORY Single Step Memory Automatic Testing Memor INTERFACE Standard (Front) Standard (Rear)	Range Resolution Accuracy tod Range Resolution Accuracy tod	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 3Vac max (open circuit) SOHz/60Hz selectable $1m\Omega - 650m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal ON/OFF 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ $0.01\Omega \pm (10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, R5-232C, USB device, Signal I/O,
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Single Step Memory Automatic Testing Memory INTERFACE Standard (Front) Standard (Rear) Option	Range Resolution Accuracy tod Range Resolution Accuracy tod	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega \sim 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal ON/OFF 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ 0.10Ω $\pm (10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) MEMORY Single Step Memory Automatic Testing Memor INTERFACE Standard (Front) Standard (Rear)	Range Resolution Accuracy tod Range Resolution Accuracy tod	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega - 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ 0.10Ω $\pm (10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Single Step Memory Automatic Testing Memory INTERFACE Standard (Front) Standard (Rear) Option	Range Resolution Accuracy tod Range Resolution Accuracy tod	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 3Vac max (open circuit) SOHz/60Hz selectable $1m\Omega - 650m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s Four Terminal ON/OFF 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ $0.01\Omega \pm (10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, R5-232C, USB device, Signal I/O,
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Single Step Memory Automatic Testing Memory Automatic Testing Memory Standard (Front) Standard (Rear) Option DISPLAY	Range Resolution Accuracy tod Range Resolution Accuracy tod	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 8Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega - 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 999.9s 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ 0.10Ω $\pm (10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Single Step Memory Automatic Testing Memory Automatic Testing Memory INTERFACE Standard (Front) Standard (Rear) Option DISPLAY	Range Resolution Accuracy nod Range Resolution Accuracy nod y	0.01A $3A \le 1 \le 8A : \pm (1\% \text{ of reading } + 0.2A); 8A < 1 \le 32A : \pm (1\% \text{ of reading } + 0.05A)$ 3Vac max (open circuit) 50Hz/60Hz selectable $1m\Omega - 650m\Omega$ $0.1m\Omega$ $\pm (1\% \text{ of reading } + 2 m\Omega)$ Yes 0.3s - 99.9s Four Terminal ON/OFF 100mA dc (fixed) $0.10\Omega - 70.00\Omega$ $0.10\Omega + 100 \text{ Jocks}$ $4(10\% \text{ of reading } + 2 \Omega)$ Yes 0.3s - 999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Metl TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Single Step Memory Automatic Testing Memory INTERFACE Standard (Front) Standard (Rear) Option DISPLAY POWER SOURCE	Range Resolution Accuracy nod Range Resolution Accuracy nod y	0.01A 3A≤I≤8A : ±(1% of reading + 0.2A); 8A <i≤32a +="" 0.05a)<br="" :="" of="" reading="" ±(1%="">8Vac max (open circuit) S0Hz/60Hz selectable 1mΩ - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s 100mA dc (fixed) 0.10Ω - 70.00Ω 0.01Ω ±(10% of reading + 2 Ω) Yes 0.3s-999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, CPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg</i≤32a>
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Single Step Memory Automatic Testing Memory INTERFACE Standard (Front) Standard (Rear) Option DISPLAY POWER SOURCE DIMENSIONS & WEIGHT	Range Resolution Accuracy tood Range Resolution Accuracy tood y	0.01A 3A ≤ 1 ≤ 8A : ±(1% of reading + 0.2A); 8A<1 ≤ 32A : ±(1% of reading + 0.05A) 8Vac max (open circuit) SOHz/60Hz selectable 1mΩ - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.10Ω - 70.00Ω 0.01Ω ±(10% of reading + 2 Ω) Yes 0.3s-999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. GPT-12000CD1B
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement CONTINUITY TEST Output-Current Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) MEMORY Single Step Memory Automatic Testing Memor INTERFACE Standard (Front) Standard (Rear) Option DISPLAY POWER SOURCE DIMENSIONS & WEIGHT	Range Resolution Accuracy tod Range Resolution Accuracy tod y C	0.01A 3A≤I≤8A:±1% of reading + 0.2A); 8A <i≤32a:±(1% +="" 0.05a)<="" of="" reading="" td=""> 8Vac max (open circuit) SOHz/60Hz selectable ImΩ - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.010L ±(10% of reading + 2 Ω) Yes 0.3s-999.9s ON/OFF MANU : 100 blocks AUTO : 100 blocks AUTO : 100 blocks AUTO : 100 blocks AUTO : 100 blocks AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. GPT - 12000CD1B</i≤32a:±(1%>
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement TiMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Dimeter Measurement Ohmmeter Measureme	Range Resolution Accuracy tod Range Resolution Accuracy tod y y 	0.01A 3A≤1≤8A : ±(1% of reading + 0.2A); 8A<1≤32A : ±(1% of reading + 0.05A) 8Vac max (open circuit) 50H2/60H2 selectable 1mΩ - 650mΩ 0.1mΩ ±(1% of reading + 2 mΩ) Yes 0.3s-999.9s 100mA dc (fixed) 0.10Ω - 70.00Ω 0.01Ω ±(10% of reading + 2 Ω) Yes 0.3s-999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. GPT-12000CD1B
GND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Meas	Range Resolution Accuracy nod Range Resolution Accuracy nod y y 	0.01A 3A≤1≤8A:±(1% of reading + 0.2A); 8A<1≤32A:±(1% of reading + 0.05A)
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Commeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Ohmmeter Ohmm	Range Resolution Accuracy nod Range Resolution Accuracy nod y y 	0.01A 3A ≤ 1 ≤ 8A : ± (1% of reading + 0.2A); 8A < 1 ≤ 32A : ± (1% of reading + 0.05A)
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Commeter Measurement Contrinulity TEST Output-Current Ohmmeter Measurement INTERFACE Standard (Front) Standard (Rear) Option DISPLAY POWER SOURCE ORDERING INFON GPT-12003 AC/DG GPT-12002 AC/DG GPT-12001 AC Elec	Range Resolution Accuracy nod Range Resolution Accuracy nod y y 	0.01A 3A≤1≤8A: ±(1% of reading + 0.2A); 8A<1≤32A: ±(1% of reading + 0.05A) Wac max (open circuit) S0Hz/f6Hz selectable InmO - 650mQ 0.1mQ ±(1% of reading + 2 mQ) Yes 0.3s-999.9s Four Terminal ON/OFF 100mA dc (fixed) 0.01Q ±(10% of reading + 2 Ω) Yes 0.3s-999.9s MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. CPT-12000CD1B OPTION Opt.1 GPIB card OPTIONL Opt.1 GPIB card OPTIONL GRA-440 Rack Adapter Panel (19', 4U GHT-113 High Voltage Test Pistol GRA-440 Rack Adapter Panel (19', 4U GHT-113 High Voltage Crownd Bond Adapter Box GHT-118 High Voltage Crownd Bond Adapter Box
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Control Control Control GND CONTINUITY TEST Output-Current Ohmmeter Measurement Window Comparator Meth TIMER (Test Time) TMERFACE Standard (Front) Standard (Rear) Option DISPLAY POWER SOURCE DIMENSIONS & WEIGHT ORDERING INFOP GPT-12003 AC/D0 GPT-12002 AC/D0 GPT-12001 AC Ele ACCESSORIES	Range Resolution Accuracy nod Range Resolution Accuracy nod y y S MATION C/IR/CB Electrical Safety Analyzer C/IR Electrical Safety Analyzer C Electrical Safety Analyzer c Electrical Safety Analyzer c Electrical Safety Analyzer	0.01A 3A≤158A : ±(1% of reading + 0.2A); 8A<1≤32A : ±(1% of reading + 0.05A) 8Vac max (open circuit) 50H2/60H2 selectable 1mQ - 650mQ 0.1mQ ±(1% of reading + 2 mQ) Yes 0.3s-999.9s 100mA dc (fired) 0.10Q ±(10% of reading + 2 Q) Yes 0.3s-999.9s MANU : 100 blocks AUTO : 100 blocks Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. GPT - 12000CD1B Opt.1 GPIB card OPTION Opt.1 GPIB card OPTIONAL ASSESSORIES GHT-113 High Voltage Test Pistol GRA-440 Rack Adapter Panel (19', 4U GHT-113 High Voltage (Caround Bond Adapter Box GHT-113 High Voltage (Caround Bond Adapter Box GHT-113 High Voltage (Caround Bond Adapter Box GHT-1205 High Voltage (Ster Probe
GND GROUND BOND Output-Current Output-Current Resolutio Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement TIMER (Test Time) Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Ohmmeter Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Oh	Range Resolution Accuracy nod Range Resolution Accuracy nod y y y Charlen Complete C	0.01A 3A ≤ 15 SA : ± (1% of reading + 0.2A); 8A <l +="" 0.05a)<br="" 32a="" :="" of="" reading="" ±(1%="" ≤="">8Vac max (open circuit) S0H2/60H2 selectable 1mD - 650mQ 0.1mQ ± (1% of reading + 2 mQ) Yes 0.3s - 999.95 MANU : 100 blocks AUTO: 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. GPT-12000CD1B OPTIONAL ASSESSORIES CHT-113 High Voltage Adpater Box CHT-113 High Voltage / Ground Bond Adapter Box CHT-232 RS232C Cable, 9-pin Female to 9-pin, null Modem for Computer</l>
GND GROUND BOND Output-Current Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Ohmmeter Measurement Ohmmeter Measurement Commeter Measurement Commeter Measurement Ohmmeter Measurement INTERFACE Standard (Front) Standard (Rear) Option DISPLAY POWER SOURCE ORDERING INFOI GPT-12004 AC/DE GPT-12003 AC/DE GPT-12001 AC Ele ACCESSORIES Quick Start Guide x 1, Key x 1, Remote term	Range Resolution Accuracy nod Range Resolution Accuracy nod y y S MATION C/IR/CB Electrical Safety Analyzer C/IR Electrical Safety Analyzer C Electrical Safety Analyzer c Electrical Safety Analyzer c Electrical Safety Analyzer	0.01A 3A ≤ 1 ≤ 8A : ± (1% of reading + 0.2A); 8A ≤ 32A : ±(1% of reading + 0.05A)</td Wac max (open circuit) S0H2/60H2 selectable InD2 - 650mQ 0.1mQ ±(1% of reading + 2 mQ) Yes 0.01mQ ±(1% of reading + 2 Q) Yes 0.01mQ ±(1% of reading + 2 Q) Yes 0.35-999.95 MANU : 100 blocks MANU : 100 blocks, Manu per auto : 10 REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB 7" color LCD AC 100V-240V ± 10%, 50Hz/60Hz; Power consumption : Max. 400VA 380(W) x 148(H) x 454(D) mm; Approx. 15kg Specifications subject to change without notice. GPT-10X Opt.1 <gpib card<="" td=""> OPTIONI Opt.1<gpib card<="" td=""> OPTIONIAL ASSESSORIES CHT-113</gpib></gpib>

GOOD WILL INSTRUMENT CO., LTD.



通信

LinkedIn



No.7-1, Jhongsing Road, Tucheng Dist., New Taipei City 236, Taiwan T +886-2-2268-0389 F +886-2-2268-0639 E-mail: marketing@goodwill.com.tw